



29 SEPTEMBER—4 OCTOBER 2013
CONVENTION CENTER, PASADENA, CALIFORNIA

Single-shot Ultrafast Electron Microscopy

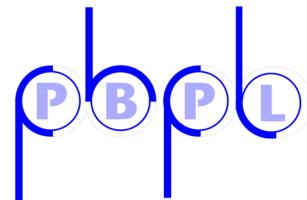
Renkai Li and Pietro Musumeci

Department of Physics and Astronomy, UCLA

25th North American Particle Accelerator Conference

Sep 30 - Oct 4, 2013, Pasadena, CA, USA

UCLA

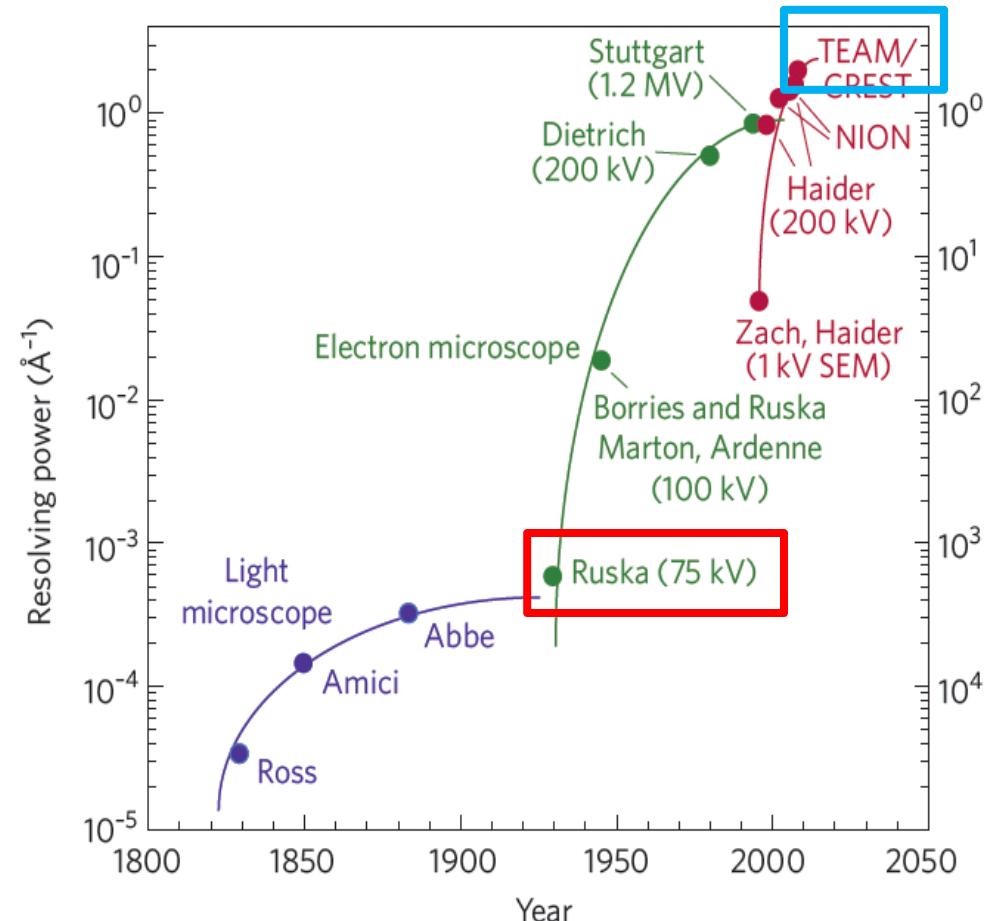


Outline

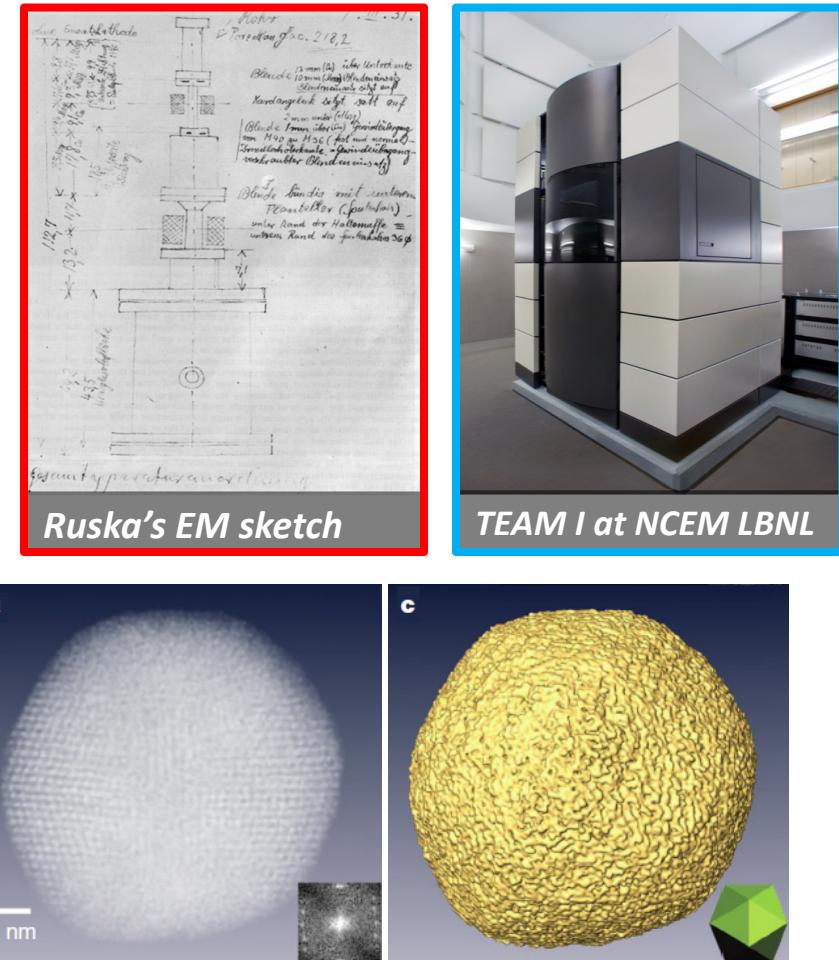
- transmission electron microscopes go ‘4D’
- **stroboscopic** and **single-shot** approaches
- single-shot, picosecond-temporal resolution UEM
based on photocathode rf guns
 - **ultralow emittance**: cigar-shape beam
 - **ultralow energy spread**: rf curvature regulation
 - **novel electron optics**: PMQ and μ -quads
- summary and outlook

Transmission electron microscopies

- ❖ primary tool for material science, chemistry, physics, biology, and industry
- ❖ sub-Ångström spatial resolution with aberration correction



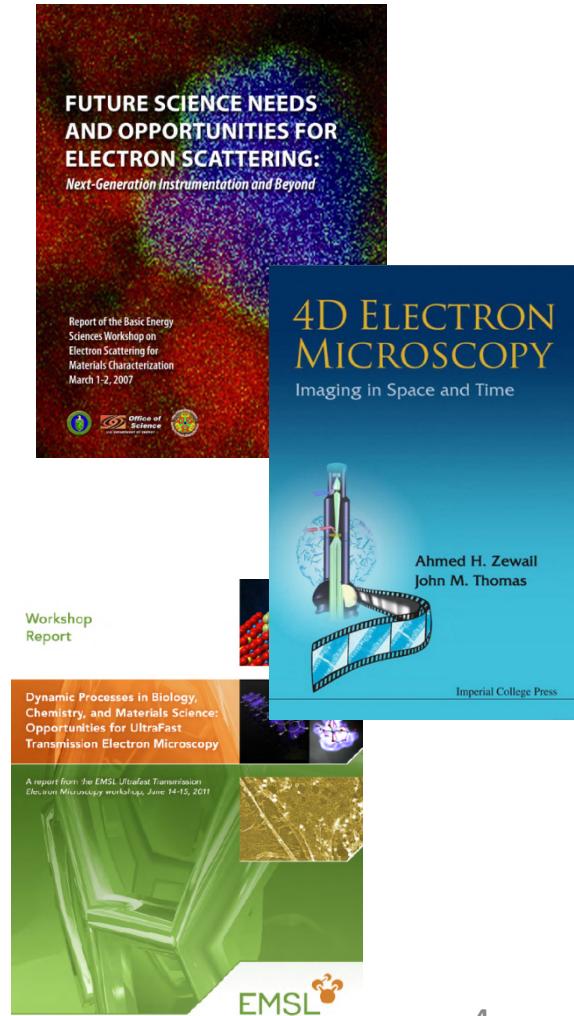
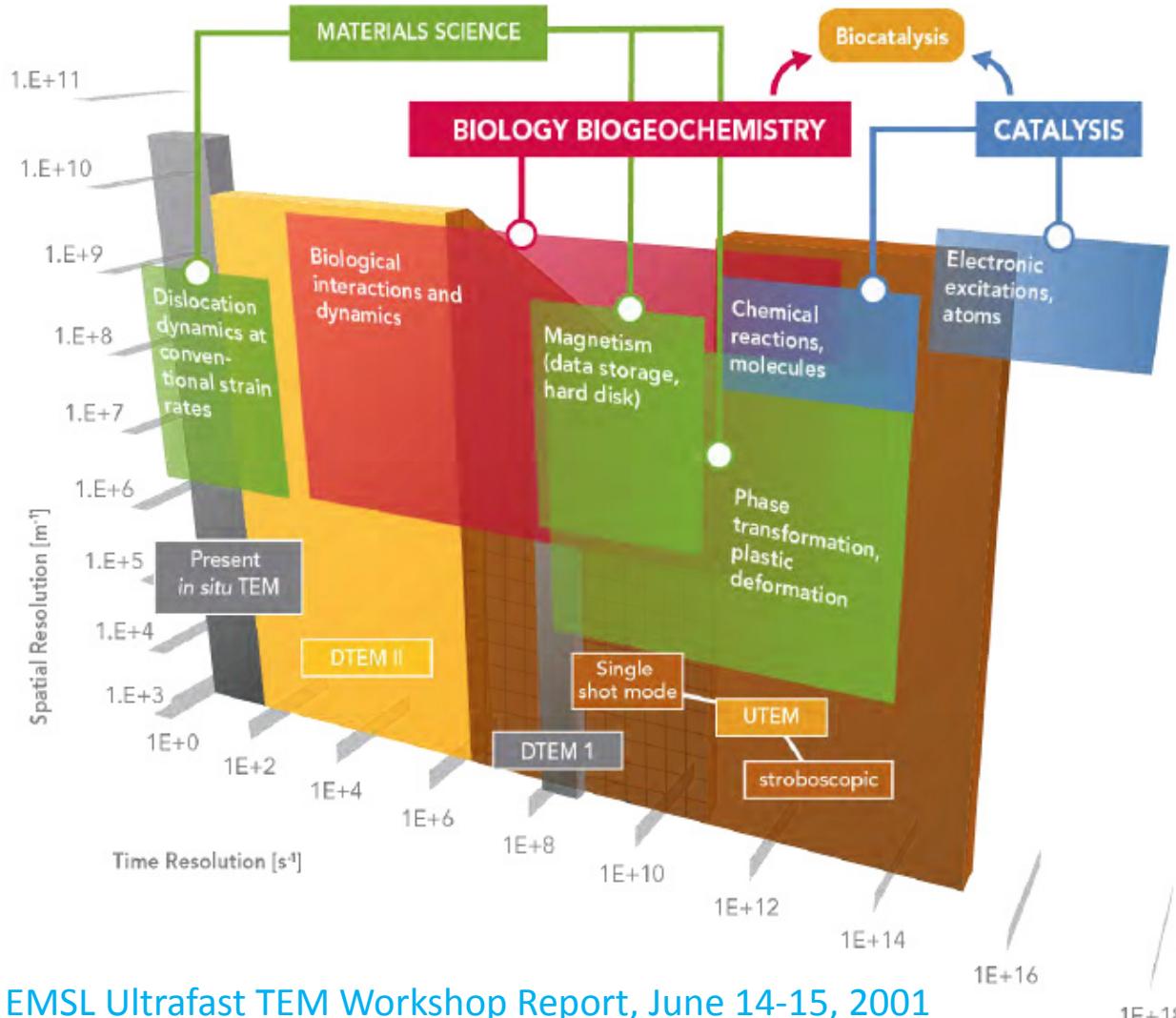
D. A. Muller, Nat. Mater. 8, 263 (2009)
Adapted from H. H. Rose (2009)



3D electron tomography at ångström resolution
M. C. Scott, Nature 444, 483 (2012)

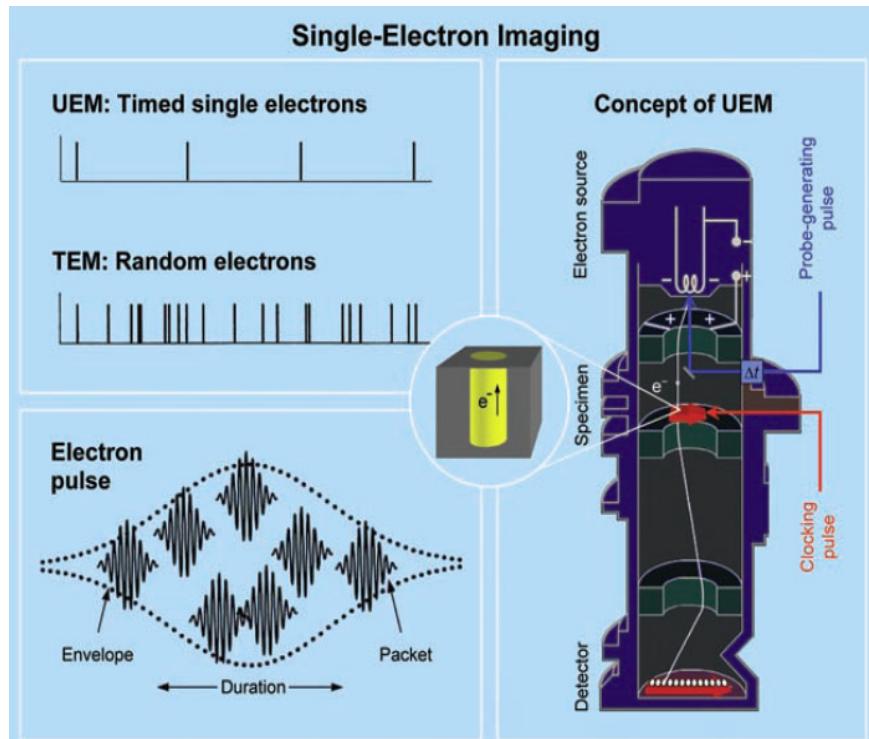
Resolution in the 4th dimension – time domain

- ❖ Conventional TEMs need millisecond to second exposure time
- ❖ many reasons to see structural **changes** in time, rather than static images



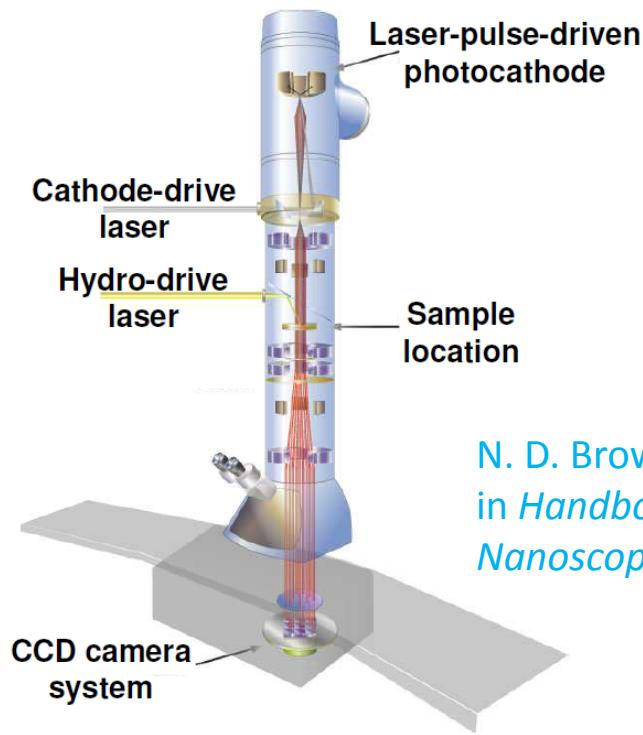
Ultrafast TEM: stroboscopic and single-shot approaches

Stroboscopic: UEM at Caltech



A. H. Zewail, Science 328, 187 (2010)

Single-shot: DTEM at LLNL



N. D. Browning et al.,
in *Handbook of Nanoscopy*, 2012

O. Bostanjoglo, in *Advan in Imag Elect Phys*, 121 (2002)

- ❖ use photocathode in conventional 200 kV TEMs, pump-probe scheme
- ❖ Stroboscopic: 1 e⁻/pulse, atomic scale resolutions, reversible processes
- ❖ Single-shot: 10⁸ e⁻/pulse, 10 nm – 15 ns resolution, irreversible processes

Single-shot UEM using photocathode rf guns

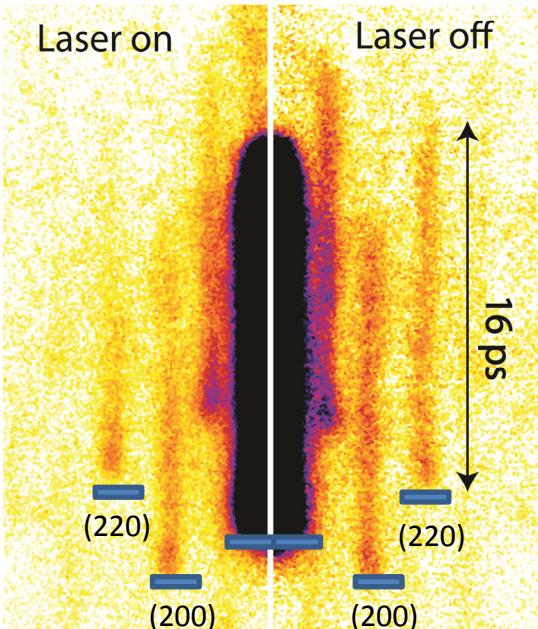
- ❖ *DTEM limited by beam brightness and space charge effects*
 - *modified conventional TEM gun, low gradient of 1 MV/m*
 - *low beam energy of 200 keV, high charge density close to sample area*

Are the low gradient gun design and low beam energy the optimal solution for ultrafast imaging applications?

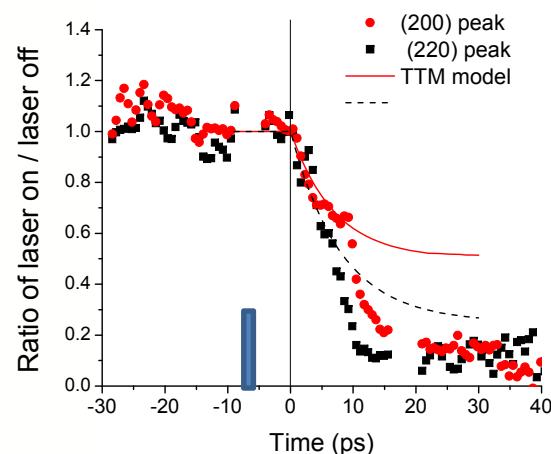
- ❖ *Photocathode rf guns*
 - *high gradient 100 MV/m, help improve beam brightness*
 - *high beam energy 3-5 MeV, greatly suppress space charge effects*

Using the beam from photocathode rf guns, it is possible to build picosecond-temporal resolution UEMs.

an exciting new field: UED and UEM

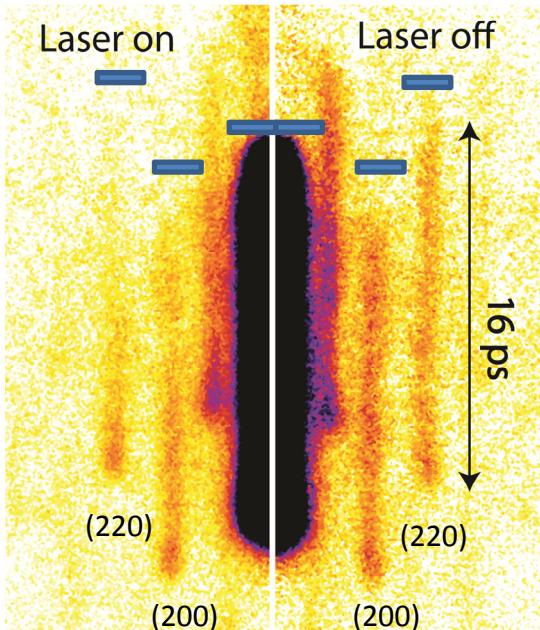


gold melting, streak-mode,
full history with one e- beam

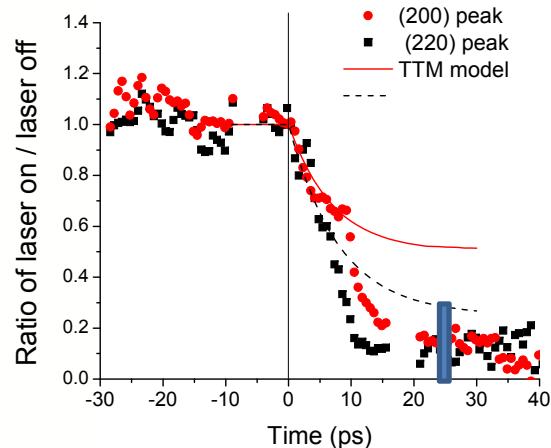


P. Musumeci et al. JAP, 108, 114513 (2010)

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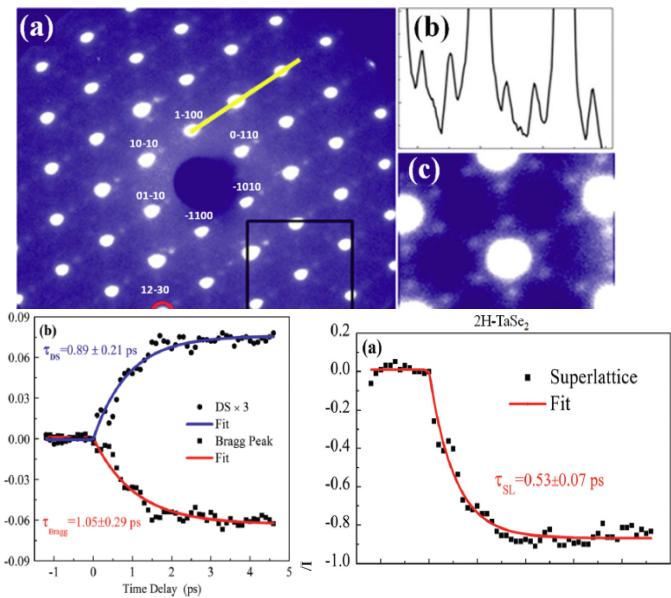


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P. Musumeci et al. JAP, 108, 114513 (2010)

CDW, very high pattern quality



P. F. Zhu et al. APL 103, 071914 (2013)

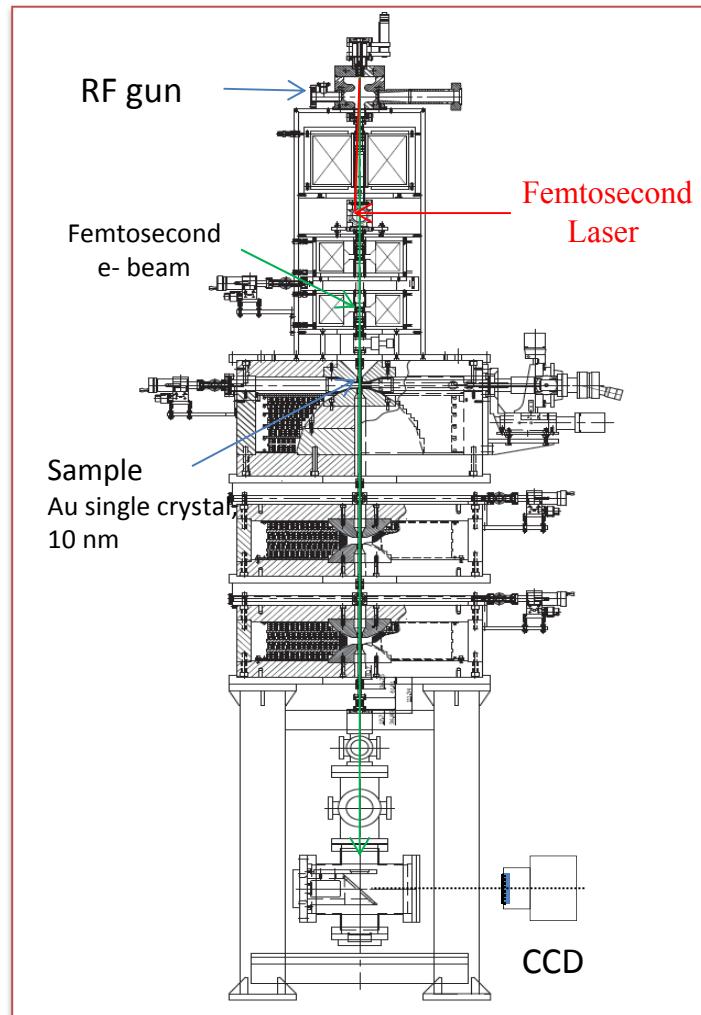
Courtesy of Xijie Wang

Recent and upcoming workshops

- ❖ Dec. 2012, Workshop on Ultrafast Electron Sources for Diffraction and Microscopy Applications http://pbpl.physics.ucla.edu/UESDM_2012/
- ❖ July 2013, Workshop on Femtosecond Transmission Electron Microscopy <http://lumes.epfl.ch/page-93264-en.html>
- ❖ Dec. 2013, FEIS 2013 - Femtosecond Electron Imaging and Spectroscopy <http://www.feis2013.org/>

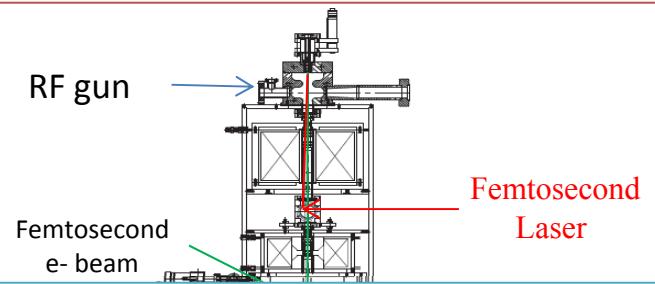
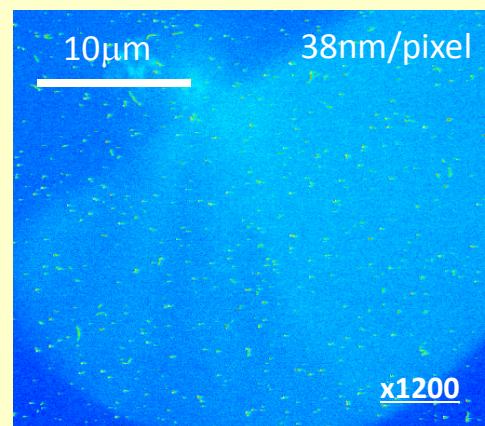
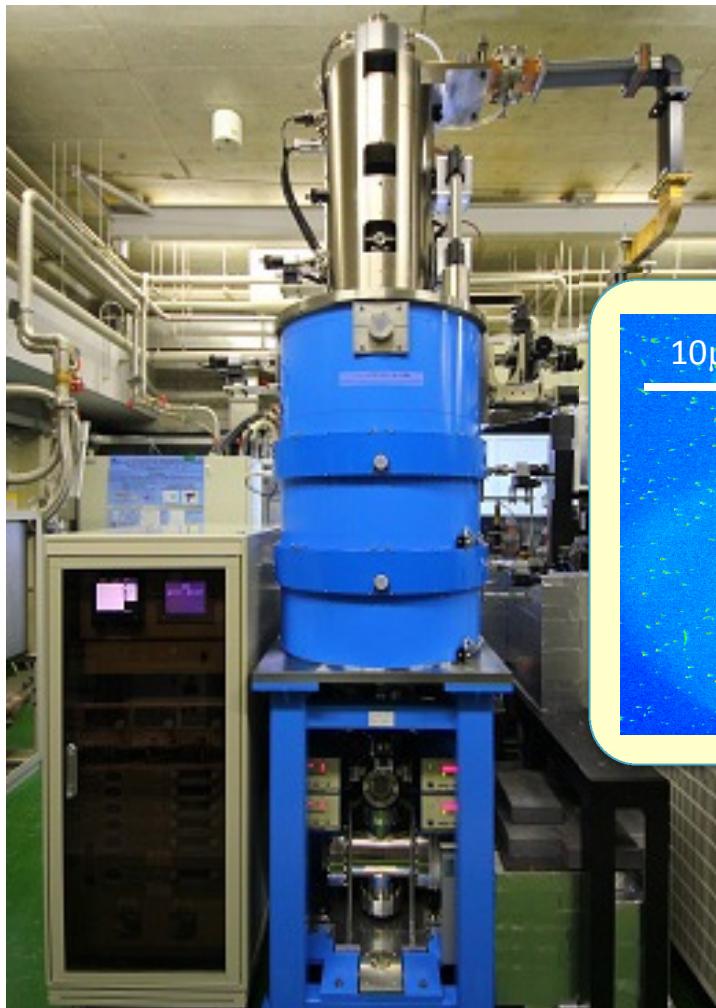
prototype rf gun based UEM at Osaka Univ.

Courtesy of Prof. Jinfeng Yang



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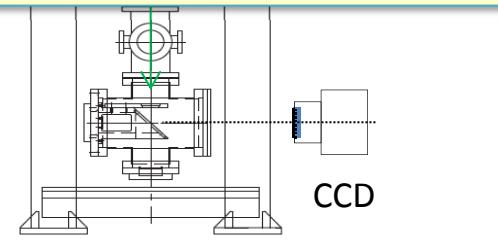
Courtesy of Prof. Jinfeng Yang



Electron charge:
 $\sim 10 \text{ fC/pulse}$
 $(10^5 \text{ e}'\text{s}/\text{pulse})$
Measurement time:
 $\sim 10 \text{ min}$



$\sim 10^8 \text{ e}'\text{s}/\text{image}$



similar UEM projects in China and Germany!

beam requirements for single-shot ps UEM

$$B = \frac{N}{4\pi^2 \sigma_x^2 \sigma_{x'}^2 \cdot \Delta t \cdot \Delta \gamma / \gamma}$$

❖ *temporal resolution (a few ps):*

- *ps bunch length: $\Delta t \sim 1 \text{ ps}$*
- *sub-ps timing between laser and electron beams*

❖ *spatial resolution (a few tens of nm):*

- *high flux at the sample (Rose' criterion): $N \sim 10^6 - 10^8$, $\sigma_x \sim 1 \mu\text{m}$*
- *low angular divergence (related to spherical aberration): $\sigma_{x'} \sim 1 \text{ mrad}$*
- *low energy spread (related to chromatic aberration): $\frac{\Delta \gamma}{\gamma} \sim 10^{-4} - 10^{-5}$*

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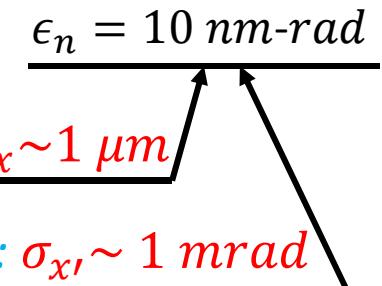
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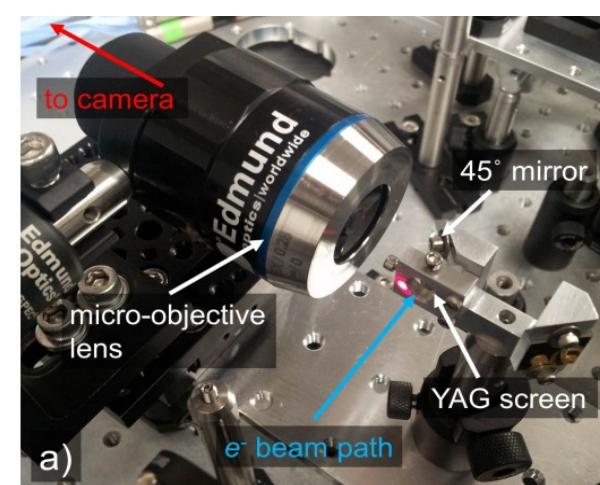
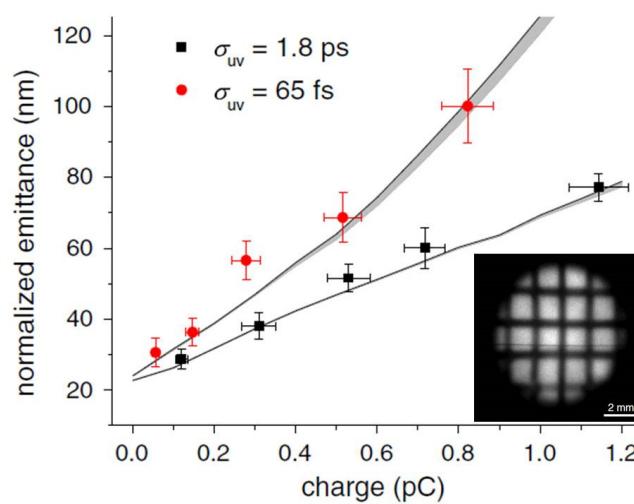
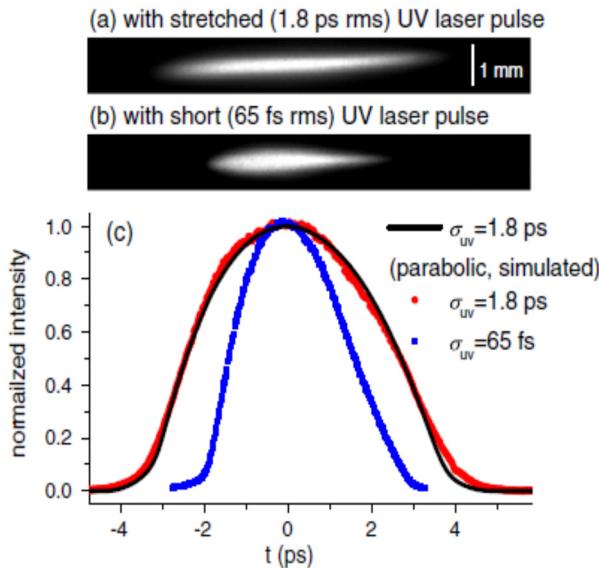


a few pC charge, ultralow emittance: Cigar-beam

- ❖ *Cigar-aspect-ratio beam: long (10 ps) and narrow (<50 μm spot size)*
 - *the aspect-ratio can beat the ‘virtual cathode limit’ D. Filippetto et al., submitted*
 - *very small intrinsic emittance from the cathode*
 - *transverse and longitudinal dynamics are essentially decoupled*

Simulation shows we can generate 5 MeV, 2 pC charge, 10 ps full width, <10 nm normalized emittance, <1 um rms spot size at the sample.

- ❖ *measurement of ultralow emittance and small spot size*

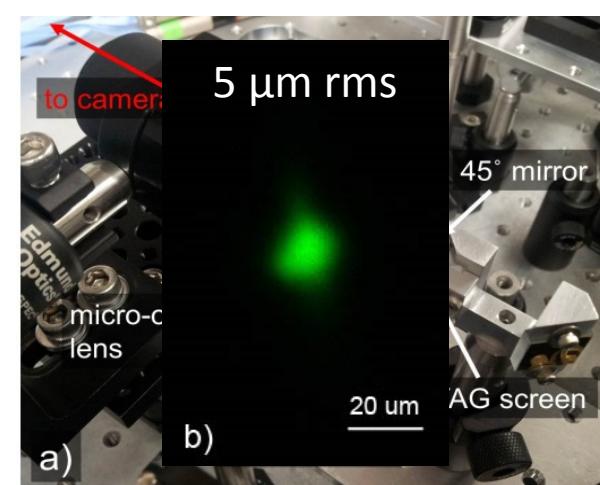
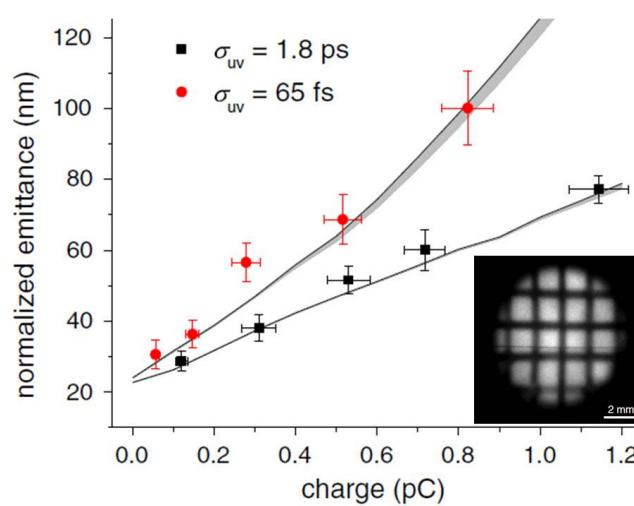
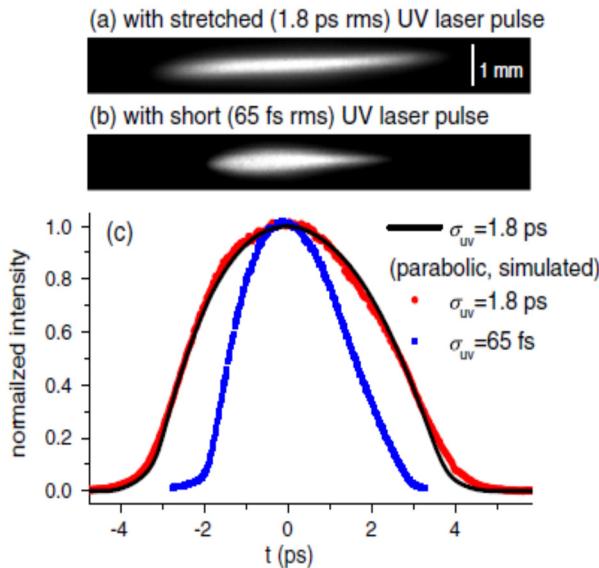


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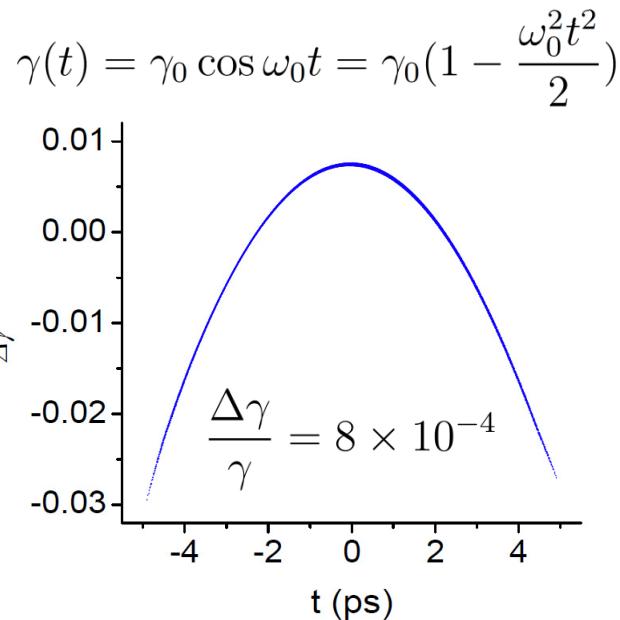


low energy spread: rf curvature regulation

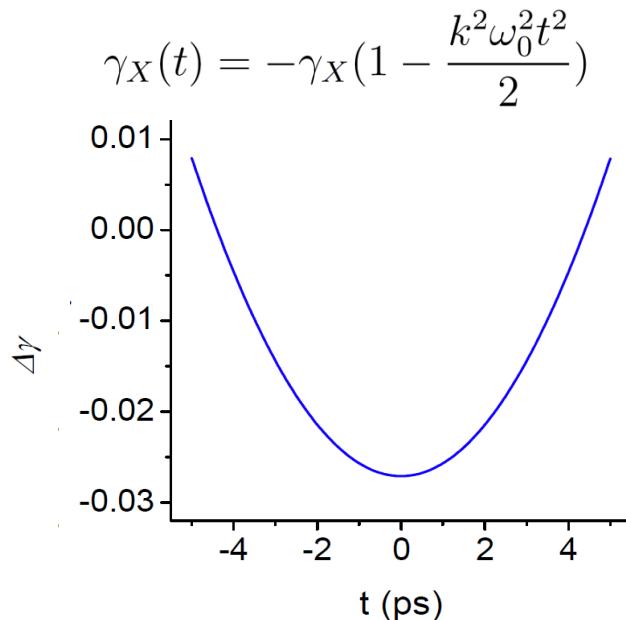
❖ beam rf curvature from rf guns

- beam energy depends on launching phase (time)
- beam energy spread dominated by the rf curvature
- slice energy spread much smaller

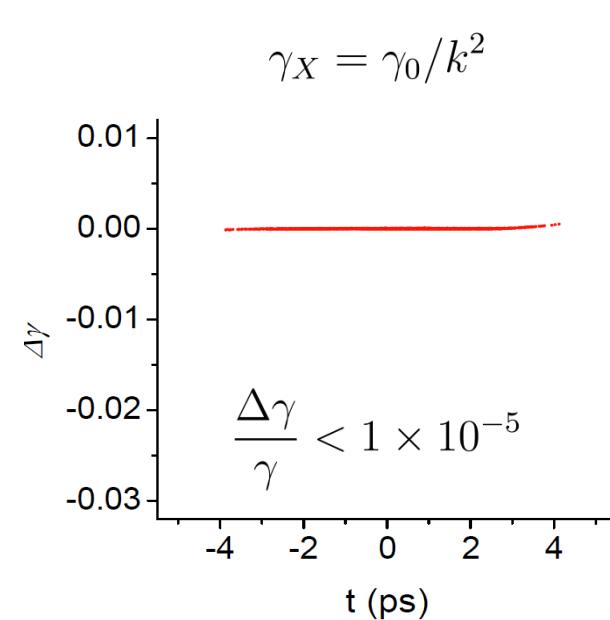
y-t at S-band gun exit



deceleration in X-band cavity



final y-t distribution

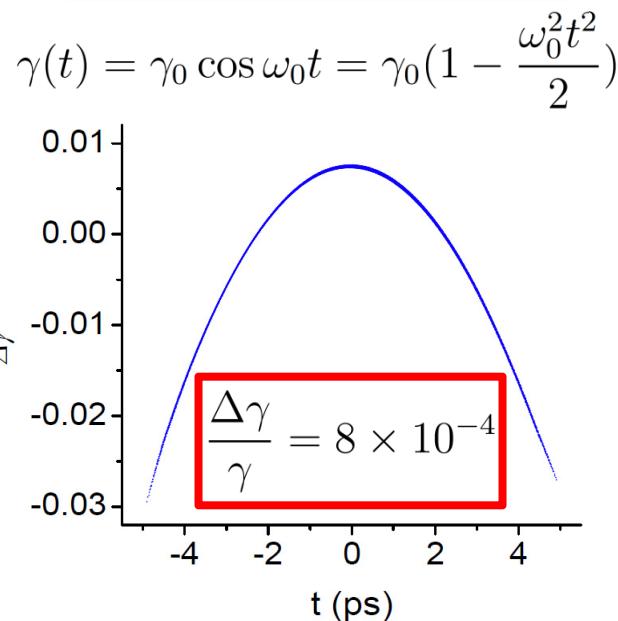


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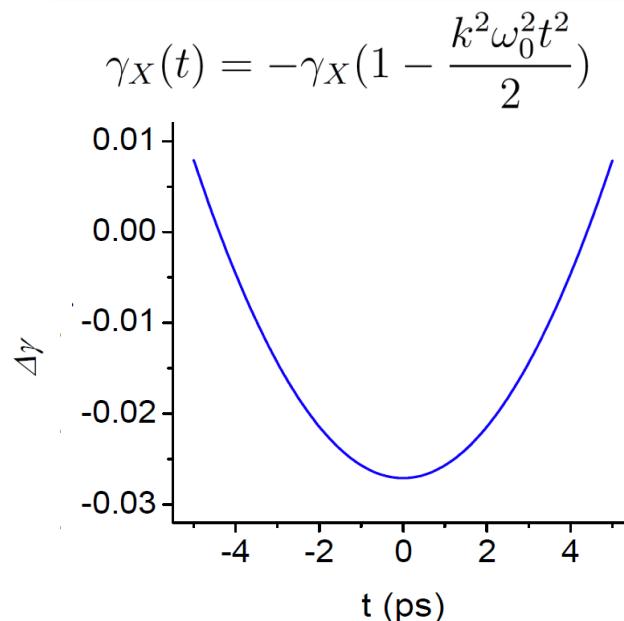
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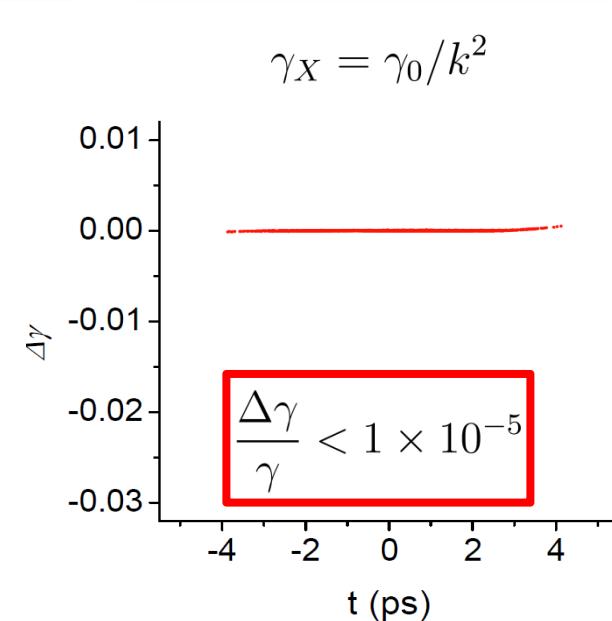
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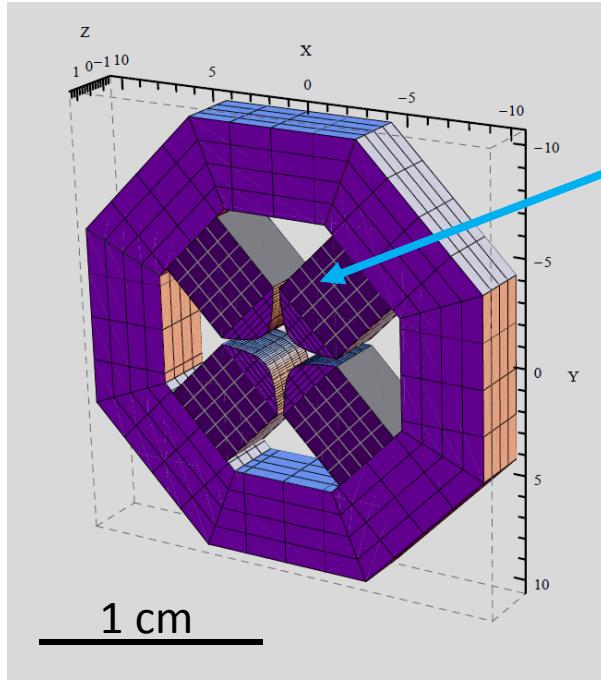


- ❖ larger $k \equiv \omega_X/\omega_0$ works better (less deceleration)
- ❖ performances limited by rf amplitude and phase stabilities

strong lenses for MeV beams

- ❖ for conventional TEMs (<300 keV), solenoid lenses are used
- ❖ solenoid is symmetric, but very ineffective for high energy electrons
- ❖ C_s and C_c are roughly equal to the focal length
- ❖ heavy and bulky NC solenoid (≤ 2.2 T), or SC solenoid can be used
- ❖ or, using quadrupoles which are strong and compact

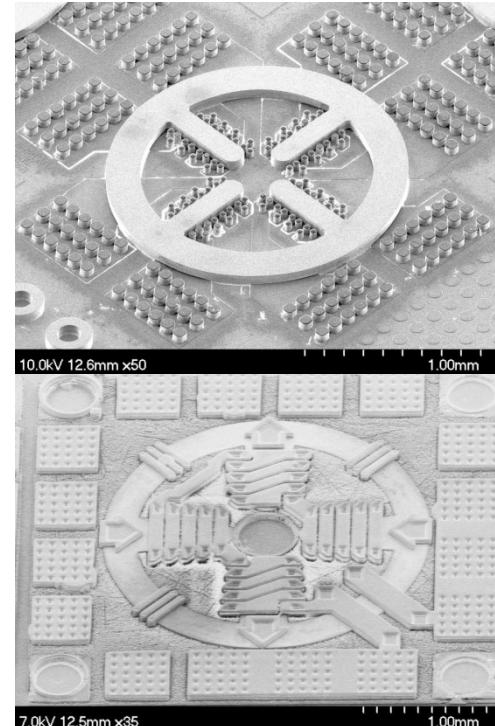
permanent magnet quadrupoles



permanent
magnets,
 $B_0=1.40$ T

gradient
 $G\sim 500$ T/m

nanofabricated micro-quads



1) gradient
 $G>1000$ T/m

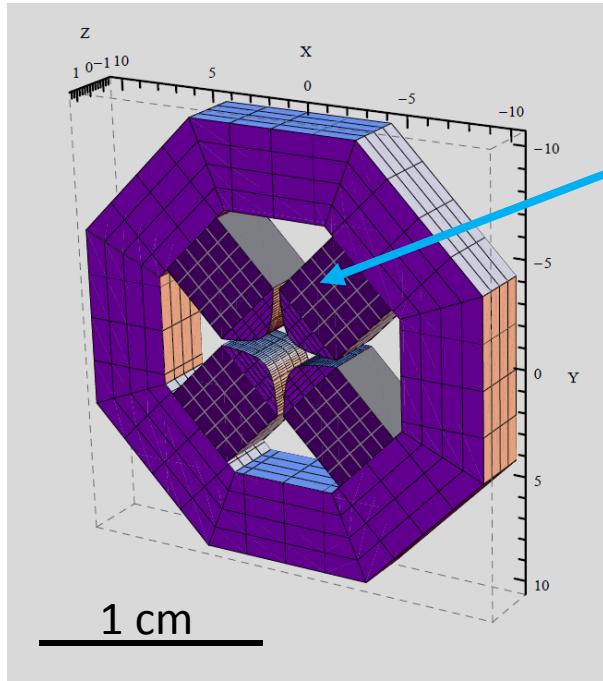
2) tunable
strength!!

Courtesy of J.
Harrison, UCLA

strong lenses for MeV beams

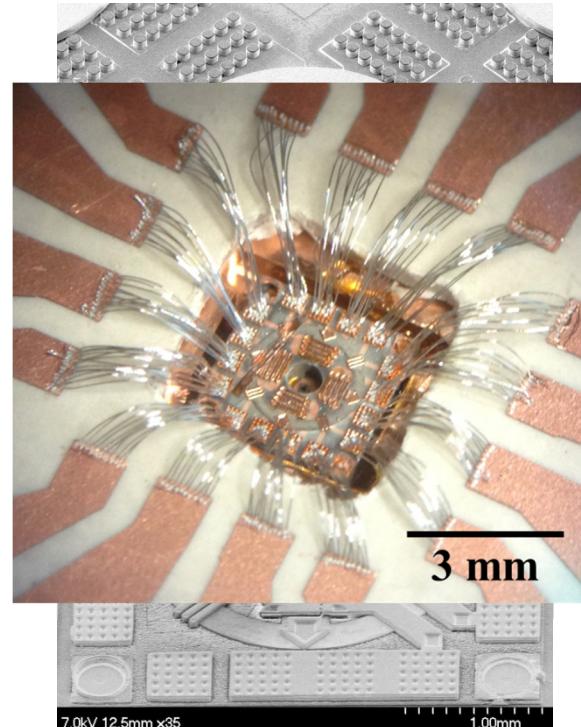
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permanent magnet quadrupoles



permanent
magnets,
 $B_0 = 1.40$ T
gradient
 $G \sim 500$ T/m

nanofabricated micro-quads

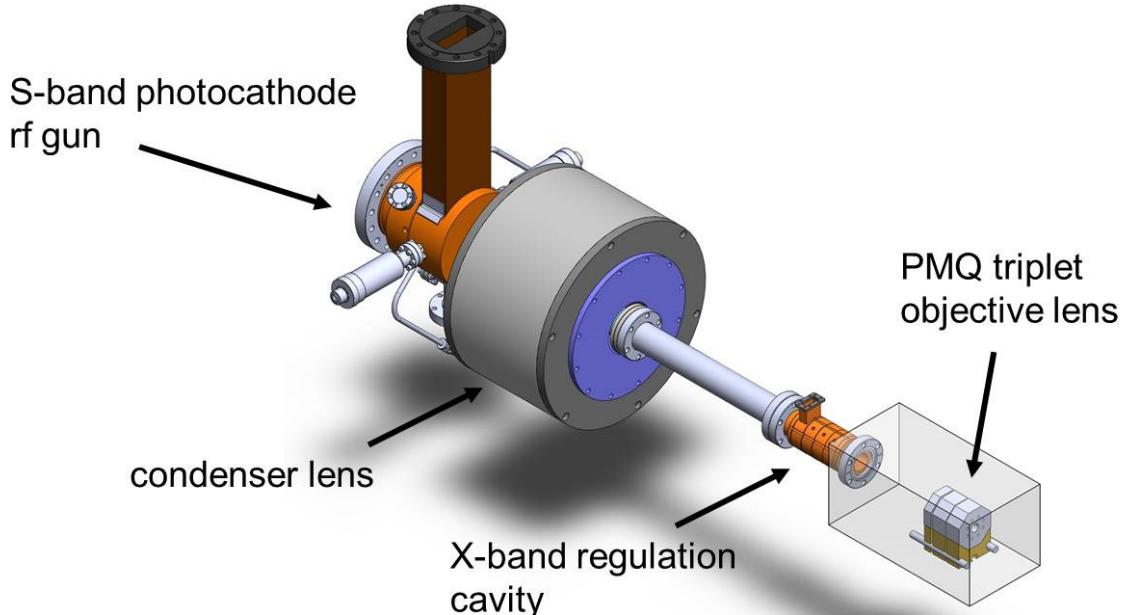


1) gradient
 $G > 1000$ T/m

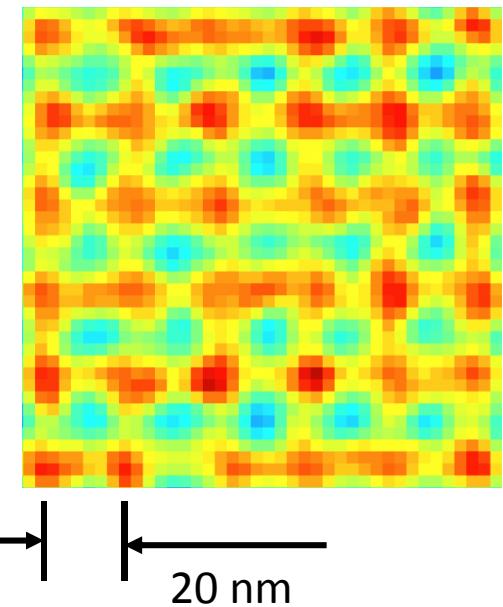
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Harrison, UCLA

key components of a single-shot ps UEM



*start-to-end simulation with
point-to-point tree code*



- ❖ *high gradient S-band rf gun see L. Faillace HBEB Workshop 2013*
- ❖ *X-band rf regulation cavity*
- ❖ *strong electron lens*
- ❖ *high efficiency detection of MeV electrons R. K. Li et al., JAP 110, 074512 (2011)*
- ❖ *rf amplitude and phase control*

Acknowledgement

- funding agencies: DOE-BES, DOE-HEP, JTO-ONR



- UCLA Pegasus Laboratory members
- O. Williams and P. Frigola on PMQ
- helpful discussions with M. Mecklenburg, B. W. Reed, J. C. H. Spence, and W. Wan

Summary

- strong motivation, clear path towards a single-shot ps UEM
- many scientific opportunities
- relatively compact and low cost facility fit into university labs
- technical approaches well defined, new technologies will help
- key parameters (emittance, energy stability and spread)
challenging but within reach
- precise control and advanced diagnosis
- R&D will also benefit light source applications

Thank you for your attention!